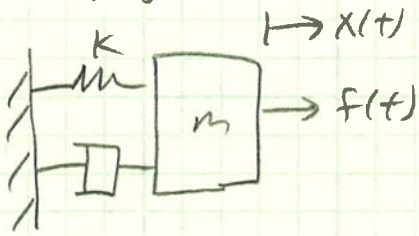


1. Applying a force to MEMS SMD device

DC Force: $F = f(t)$ steady state: $\ddot{x} = \dot{x} = 0 \therefore x = \frac{F}{k}$

$$m\ddot{x} + c\dot{x} + kx = f(t)$$

force $f(t)$ results in proof mass motion, $x(t)$

→ Often, a sinusoidal force is applied at ω_n to take advantage of high $Q \rightarrow$ low $f(t) \rightarrow$ high $x(t)$

let $f(t) = F \cos(\omega_n t)$ where $\omega_n = \sqrt{\frac{k}{m}}$

$$\therefore m\ddot{x} + c\dot{x} + kx = F \cos(\omega_n t)$$

→ assume solution of the form $x(t) = A \sin(\omega_n t)$

$$\therefore \dot{x}(t) = A \omega_n \cos(\omega_n t)$$

$$\therefore \dot{x}'(t) = -A \omega_n^2 \sin(\omega_n t)$$

$$\rightarrow \overset{\substack{\uparrow \\ \text{sin terms}}}{m\ddot{x}} + \overset{\substack{\uparrow \\ \text{sin terms}}}{c\dot{x}} + \overset{\substack{\uparrow \\ \text{sin terms}}}{kx} = f(t)$$

∴ equate trig terms

$$\rightarrow cA\omega_n \cos(\omega_n t) = F \cos(\omega_n t)$$

$$\therefore A = \frac{F}{c\omega_n}$$

$$\therefore x(t) = \frac{F}{c\omega_n} \cos(\omega_n t) = \frac{FQ}{m\omega_n^2} \cos(\omega_n t) \rightarrow Q \uparrow : x(t) \uparrow$$

 $f(t) \propto \cos(\omega_n t)$ and $x(t) \propto \sin(\omega_n t)$ ∴ at ω_n , motion lags force by 90°

→ important in feedback systems

3-0235 — 50 SHEETS — 5 SQUARES
 3-0236 — 100 SHEETS — 5 SQUARES
 3-0237 — 200 SHEETS — 5 SQUARES
 3-0137 — 200 SHEETS — FILLER

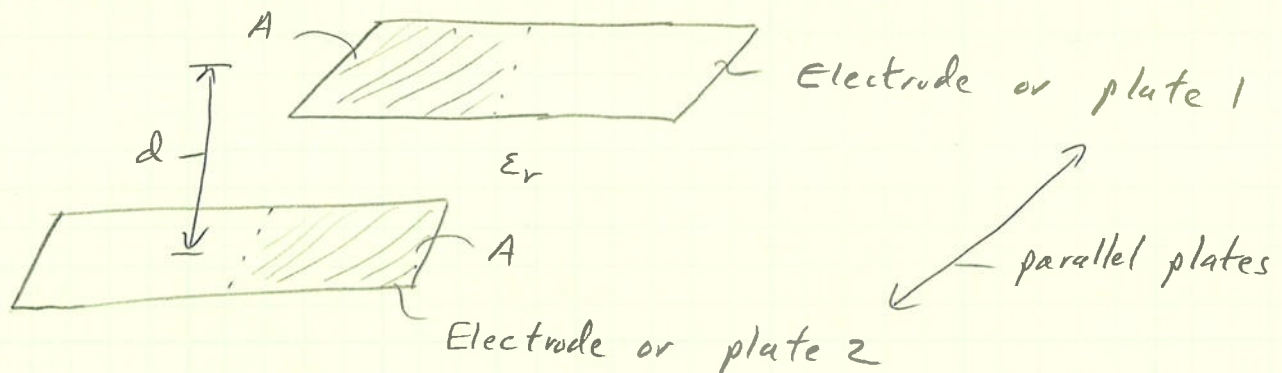
COMET

1. Chapter 4 (p. 127+) Electrostatic Sensing and Actuation

→ Capacitors heavily used to sense + actuate in MEMS

→ Capacitance is an "area effect" → scales favorably in MEMS

a. Structure



$A \equiv$ overlapping area

$d \equiv$ plate separation distance

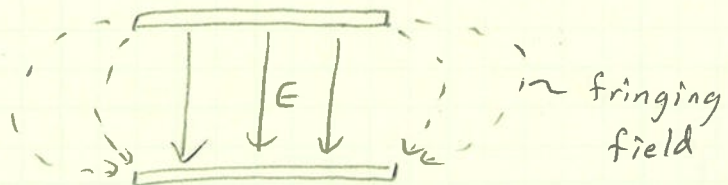
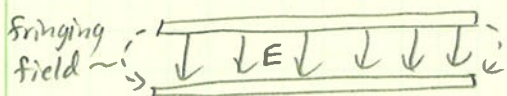
$\epsilon_r =$ "relative permittivity" or "dielectric constant" of the electrically insulating material between the plates

$\epsilon_0 = 8.854 \text{ pF/m} \rightarrow$ permittivity of free space

$$C = \frac{\epsilon_0 \epsilon_r A}{d}, [C] = F$$

↳ this formula ignores fringing effects

→ reasonable if $d \ll \sqrt{A} \Rightarrow$ often the case in MEMS



↳ fringing fields of more importance here

$$C = \frac{\epsilon_0 \epsilon_r A \beta}{d} \quad \text{where } \beta \equiv \text{fringing effect correction factor}$$

a. Capacitive Sensing Techniques

① plate separation : $d(t)$ or $d(x)$ \rightarrow often used in MEMS

$$C(t) = \frac{\epsilon_0 \epsilon_r A}{d(t)} \quad \left\{ \text{ignoring fringing} \right\}$$

$$C(t) \propto \frac{1}{d(t)} \text{ or } \frac{1}{\text{measurand}} \quad \left\{ \text{measurand} \equiv \text{quantity being sensed} \right\}$$

② area separation : $A(t)$ or $A(x)$

$$C(t) = \frac{\epsilon_0 \epsilon_r A(t)}{d}$$

$$C(t) \propto A(t) \text{ or measurand}$$

$A(t) \rightarrow$ 2-D motion

if $A(t) = X Y(t) \rightarrow$ 1-D motion where $A(t) = X Y(t)$

$$\rightarrow C(t) = \frac{\epsilon_0 \epsilon_r X Y(t)}{d}$$

$$C(t) \propto Y(t) \text{ or measurand}$$

③ dielectric constant : $\epsilon_r(t)$ or $\epsilon_r(x)$

$$C(t) = \frac{\epsilon_0 \epsilon_r(t) A}{d}$$

$$C(t) \propto \epsilon_r(t) \text{ or measurand}$$

④ fringing fields : $\beta(t)$ or $\beta(x)$

\rightarrow measurand interacts with the fringing fields

$$C(t) = \frac{\epsilon_0 \epsilon_r A \beta(t)}{d}$$

$$C(t) \propto \beta(t) \text{ or measurand}$$